

Form PTO-144

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.
M122-1684

SERIAL NO.
09/827,348

LIST OF ART CITED BY APPLICANT
(See several sheets if necessary)

APPLICANT
Micon Technology, Inc.

FILING DATE
April 4, 2001

GROUP
2829

U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
VN	AA	4,006,909	2/8/1977	Oliendorf et al.			
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

AI		
AJ		
AK		
AL		

EXAMINER *mb Nguyen*

DATE CONSIDERED 09/08/04

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

JUL 16 2004
 PATENT & TRADEMARK OFFICE

Form PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. M122-16804	PRIORITY SERIAL NO. 09/137.629
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)		APPLICANT David R. Membree	
		PRIORITY FILING DATE August 21, 1998	PRIORITY GROUP 2629

U.S. PATENT DOCUMENTS


*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
VN	AA	4,560,216	12/24/85	Egawa		
↓	AB	4,754,555	7/5/88	Stillman		
↓	AC	5,475,317	12/12/95	Smith		
↓	AD	5,495,667	3/5/96	Farnworth et al.		

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, ETC.)

VN	AB	 CAN. 68,884-184, Filed 3/22/98; Applicant's Amendment filed 10/10/98; CIPA filed 5/28/99; Amendment filed 3/3/00; Amendment filed 3/23/99; Original Application filed 3/23/98; Pending Claims
↓	AF	Advertisement for Probe Technology; www.idinet.com ; Interconnect Devices, Inc.; 1 page; 3/6/98
↓	AG	Good Things Come In Small BGA/CSP Packages; www.johnstech.com/4/handbook/page9.html ; 1 page; 3/5/98
↓	AH	Product Description for Double Ended Probes, B1052 Series; www.testprobe.com/products/b1052.html ; Rika Denshi America, Inc.; 1 page; 2/4/98.
↓	AI	Product Description for Test Centers, RM-500 Series Probes, www.testprobe.com/products/rm500.html ; Rika Denshi America, Inc.; 1 page; 2/4/98.
↓	AJ	Product Description for Cost Effective Interconnections for High I/O Products; www.testprobe.com/products/io.htm#b1303 ; Rika Denshi America, Inc.; 1 page; 2/4/98.
↓	AK	Product Description for Ball Grid Probe B1303-C3; www.testprobe.com/products/io.htm#b1303 ; Rika Denshi America, Inc.; 1 page; 2/4/98.
↓	AL	Product Description for Test Socket Contacts; www.johnstech.com/4/handbook/page9.html ; 1 page; 3/5/98

EXAMINER <i>mh Nguyen</i>	DATE CONSIDERED <i>09/08/04</i>
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Form PTO-1449				U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1684		SERIAL NO. 09/827,248	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)						APPLICANT Micron Technology, Inc.			
						FILING DATE April 4, 2001		GROUP 2829	
U.S. PATENT DOCUMENTS									
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate		
VN	AA	5,503,034	4/2/1996	Amano et al.					
VN	AB	5,964,395	2/1/2000	Giovastky et al.					
VN	AC	5,645,764	7/1997	Angelopoulos et al.					
VN	AD	5,437,189	8/1995	Brown et al.					
	AE								
	AF								
	AG								
	AH								
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)									
	AI								
	AJ								
	AK								
	AL		EV372455367						
EXAMINER <i>mh Nguyen</i>				DATE CONSIDERED 09/08/04					
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